

**Search Notes**

Application/Control No.

10/812,526

Examiner

David J. Makiya

Applicant(s)/Patent under  
Reexamination

LEE ET AL.

Art Unit

2875

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated search in EAST attached	4/27/2006	DJM